

Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2022

Based on structural similarity

| Supplier | | User Part Number | | | | |
|--|--|-----------------------------|-----------|------------|-----------|--|
| Nexperia B.V. | | 74HCT2G00DP-Q100 | | | | |
| Part Description: Dual 2-input NAND gate; TTL enabled | | | | | | |
| Function Family: HC(T) Process family: Super micron Package family: TSSOP | | | | | | |
| JESD47 Test | Test Conditions | Duration | # Lots | # Quantity | # Rejects | |
| # 1 TEST Pre- and Post-Stress Electrical Test | Tamb = 25 °C | N/A | see below | all parts | see below | |
| # 2 PC Preconditioning | JESD22-A113 MSL 1 | N/A | 1070 | 83683 | 0 | |
| # 5a HTOL EFR High Temperature Operating Life Extrinsic | JESD22-A108 Tj = 150°C V _{CCMAX} ≤ V ≤ 1.2*V _{CCMAX} | 48 hours or 168 hours | 136 | 39090 | 0 | |
| # 5b HTOL IFR High Temperature Operating Life Intrinsic | JESD22-A108 Tj = 150°C V _{CCMAX} ≤ V ≤ 1.2*V _{CCMAX} | ≥500 hours | 84 | 5695 | 0 | |
| # 7 TC Temperature Cycling | JESD22-A104 -65 °C to 150°C | ≥500 cycles | 549 | 43127 | 0 | |
| # 9 uHAST / HAST unbiased or biased High Accelerated Stress Test | JESD22-A101 Tamb = 130 °C, RH = 85%, V = V _{CCMAX} | 96 hours | 521 | 40556 | 0 | |

Calculation of PPM, FIT and MTTF

Test considered for PPM calculation: High Temperature Operating LifeTest Extrinsic (HTOL EFR, Test # 5a above)

Test considered for FIT and MTTF calculations: High Temperature Operating LifeTest Intrinsic (HTOL IFR, Test # 5b above)

Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

| Product Family | Package Family | Quantity | Rejects | Extrinsic Failure Rate (PPM) | Intrinsic Failure Rate (FIT) | MTTF (hrs) |
|----------------|----------------|----------|---------|------------------------------|------------------------------|------------|
| HC(T) | TSSOP | 5695 | 0 | 24 | 0.6 | 1.74 E+09 |